


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/710,935	CHEN ET AL.	
	Examiner	Art Unit	
	DAVID VU	2818	

SEARCHED			
Class	Subclass	Date	Examiner
257	315-319; 365; E29.129	10/11/2006	DV
	E29.3	10/11/2006	DV
	E21.68	10/11/2006	DV
438	257, 266	10/11/2006	DV

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	10/11/2006	DV
EAST	10/11/2006	DV